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The pyrometric cone equivalent test is described in ASTM Standard C24-56.

Chapter 10

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LeBret, J.B. & MGN.

Figure 10.3

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Figure 10.30

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Figure 10.33

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Figure 12.11c

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From the ERSF-NL38 newsletter. This plate can be seen in the Museo Regionale della Ceramica di Deruta in Italy. Deruta is a beautiful city, overlooking the Tiber valley, renowned for its ceramic art dating back to the Middle Ages. See: www.museoceramicaderuta.it and www.deruta.net.

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Courtesy of Jim Robison.

Figure 23.11b

Courtesy of Michael Sherrill.

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Figure 24.27

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Courtesy of Keko Equipment (Slovenia) and Haiku Tech, Inc. (USA).

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Courtesy of Richard Hughes. See also his web site www.ruby-sapphire.com.

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Figure 36.8a

Courtesy of A.Krüß Optronik GmbH, Hamburg, Germany (Karin Leibrock).

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